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 State-of-the-Art Advanced BiCMOS Technology (ABT) Design for 3.3-V Operation and Low-Static Power 	SN54LVTH16244A WD PACKAGE SN74LVTH16244A DGG OR DL PACK (TOP VIEW)	
Dissipation		
 Members of the Texas Instruments 	1OE 1 48 2OE 1Y1 2 47 1A1	
<i>Widebus</i> ™ Family	1Y2 3 46 1A2	
 High-Impedance State During Power Up 	GND 4 45 GND	
and Power Down		
 Support Mixed-Mode Signal Operation 	1Y4 [6 43] 1A4	
(5-V Input and Output Voltages With	V_{CC} 7 42 V_{CC}	
3.3-V V _{CC})	2Y1 8 41 2A1	
 Support Unregulated Battery Operation 	2Y2 9 40 2A2	
Down to 2.7 V	GND [10 39] GND	
 Typical V_{OLP} (Output Ground Bounce) 	2Y3 🛛 11 38 🗍 2A3	
< 0.8 V at V_{CC} = 3.3 V, T_A = 25°C	2Y4 🛛 12 37 🕽 2A4	
 ESD Protection Exceeds 2000 V Per 	3Y1 🛛 13 36 🗍 3A1	
MIL-STD-883, Method 3015; Exceeds 200 V	3Y2 🛛 14 35 🗍 3A2	
Using Machine Model (C = 200 pF, R = 0)	GND 🛛 15 34 🗍 GND	
	3Y3 🛛 16 33 🗍 3A3	
Latch-Up Performance Exceeds 500 mA Per	3Y4 🛛 17 32 🗍 3A4	
JEDEC Standard JESD-17	V _{CC}	
 Bus Hold on Data Inputs Eliminates the 	4Y1 🛛 19 🛛 30 🗍 4A1	
Need for External Pullup/Pulldown	4Y2 🛛 20 29 🗍 4A2	
Resistors	GND 🛛 21 28 🗍 GND	
 Power Off Disables Inputs/Outputs, 	4Y3 🛛 22 27 🗋 4A3	
Permitting Live Insertion	4Y4 🛛 23 26 🗋 4A4	
 Package Options Include Plastic 300-mil 	4 0E [24 25] 3 0E	

Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages, and 380-mil Fine-Pitch Ceramic Flat (WD) Package Using 25-mil Center-to-Center Spacings

description

The 'LVTH16244A are 16-bit buffers and line drivers designed for low-voltage (3.3-V) V_{CC} operation, but with the capability to provide a TTL interface to a 5-V system environment. These devices can be used as four 4-bit buffers, two 8-bit buffers, or one 16-bit buffer. These devices provide true outputs and symmetrical active-low output-enable (OE) inputs.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

When V_{CC} is between 0 and 1.5-V, the devices are in the high-impedance state during power up or power down. However, to ensure the high-impedance state above 1.5-V, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74LVTH16244A is available in TI's shrink small-outline (DL) and thin shrink small-outline (DGG) packages, which provide twice the I/O pin count and functionality of standard small-outline packages in the same printed circuit board area.



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description (continued)

The SN54LVTH16244A is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74LVTH16244A is characterized for operation from -40°C to 85°C.

FUNCTION TABLE (each buffer)									
INPUTS OUTPUT									
OE	Α	Y							
L	Н	Н							
L	L	L							
н	х	Z							

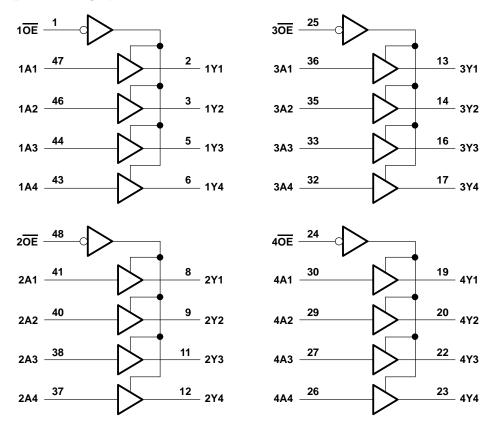
logic symbol[†]

	1 .				l	
1 <mark>0E</mark>		EN1				
2 <mark>0E</mark>	48	EN2				
3OE	25	EN3				
	24					
4OE	L	EN4				
4 4 4	47		1		2	4.1/4
1A1	46			IV	3	1Y1
1A2	44	┣───			5	1Y2
1A3	43	 			6	1Y3
1 A 4	41	 			8	1Y4
2A1	40		1	2 ▽	9	2Y1
2A2	38				11	2Y2
2A3		-				2Y3
2A4	37				12	2Y4
3A1	36		1	3 ▽	13	3Y1
3A2	35				14	3Y2
3A3	33				16	3Y3
	32				17	
3A4	30				19	3Y4
4A1	29	 	1	4 ▽	20	4Y1
4A2	27				22	4Y2
4A3						4Y3
4A4	26				23	4Y4

 † This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V _{CC} 0.5 V to 4.6 V
Input voltage range, V _I (see Note 1)
Voltage range applied to any output in the high state or power-off state, V _O (see Note 1)0.5 V to 7 V
Current into any output in the low state, I _O : SN54LVTH16244A
SN74LVTH16244A
Current into any output in the high state, I _O (see Note 2): SN54LVTH16244A
SN74LVTH16244A 64 mA
Input clamp current, I _{IK} (V _I < 0)
Output clamp current, I _{OK} (V _O < 0)
Maximum power dissipation at $T_A = 55^{\circ}C$ (in still air) (see Note 3): DGG package
DL package 1.2 W
Storage temperature range, T _{stg}

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

- 2. This current flows only when the output is in the high state and $V_O > V_{CC}$.
- 3. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils. For more information, refer to the *Package Thermal Considerations* application note in the *ABT Advanced BiCMOS Technology Data Book*.



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recommended operating conditions (see Note 4)

			SN54LVTH	16244A	SN74LVTH	16244A	UNIT
			MIN	MAX	MIN	MAX	UNIT
VCC	Supply voltage		2.7	3.6	2.7	3.6	V
VIH	High-level input voltage	2	M	2		V	
VIL	Low-level input voltage		0.8		0.8	V	
VI	Input voltage	20	5.5		5.5	V	
ЮН	High-level output current	57	-24		-32	mA	
IOL	Low-level output current		201	48		64	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	Outputs enabled	90	10		10	ns/V
$\Delta t / \Delta V_{CC}$	Power-up ramp rate		Q 200		200		μs/V
Т _А	Operating free-air temperature	-55	125	-40	85	°C	

NOTE 4: Unused control inputs must be held high or low to prevent them from floating.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CON	SN54L	VTH1624	4A	SN74L	VTH1624	4A	UNIT		
FAI	XAMEIER	TEST CON	MIN	TYP†	MAX	MIN	TYP†	MAX	UNIT		
VIK		V _{CC} = 2.7 V,	lj = -18 mA			-1.2			-1.2	V	
		V _{CC} = 2.7 V to 3.6 V,	I _{OH} = −100 μA	V _{CC} -0.2			V _{CC} -0.2				
M		V _{CC} = 2.7 V,	I _{OH} =8 mA	2.4			2.4				
VOH			I _{OH} = -24 mA	2						V	
	V _{CC} = 3 V		I _{OH} = -32 mA				2				
			I _{OL} = 100 μA			0.2			0.2		
		$V_{CC} = 2.7 V$	I _{OL} = 24 mA			0.5			0.5		
M			I _{OL} = 16 mA			0.4			0.4	v	
VOL			I _{OL} = 32 mA			0.5			0.5	V	
		V _{CC} = 3 V	I _{OL} = 48 mA			0.55					
			I _{OL} = 64 mA						0.55		
		V _{CC} = 0 or 3.6 V,	V _I = 5.5 V		ľ.	10			10		
1.	Control inputs	V _{CC} = 3.6 V,	V _I = V _{CC} or GND		N.	±1			±1		
II Data inputs		a inputs $V_{CC} = 3.6 V$	$V_I = V_{CC}$		A.	1			1	μA	
	Data inputs		V _I = 0		~	-5			-5		
loff	-	$V_{CC} = 0$, V_{I} or $V_{O} = 0$	to 4.5 V	<i></i>	5	±100			±100	μΑ	
	Detainente		V _I = 0.8 V	75 75		75			•		
l(hold)	Data inputs	V _{CC} = 3 V	V _I = 2 V	275			-75			μA	
IOZH	-	V _{CC} = 3.6 V,	V _O = 3 V			5			5	μΑ	
IOZL		V _{CC} = 3.6 V,	V _O = 0.5 V			-5			-5	μΑ	
IOZPU [‡]		$\frac{V_{CC}}{OE} = 0$ to 1.5 V, V _O = 0	= 0.5 V to 3 V,			±100			±100	μΑ	
I _{OZPD} ‡		$\frac{V_{CC}}{OE} = 1.5 \text{ V to } 0, \text{ V}_{O} = 0$	= 0.5 V to 3 V,			±100			±100	μA	
			Outputs high		0.1	0.19			0.19		
ICC		$V_{CC} = 3.6 \text{ V}, \text{ I}_{O} = 0,$ $V_{I} = V_{CC} \text{ or GND}$	Outputs low			5			5	mA	
			Outputs disabled			0.19			0.19		
∆ICC§	$V_{CC} = 3 V \text{ to } 3.6 V,$ One input at $V_{CC} - 0.6 V,$ Other inputs at V_{CC} or GND				0.2			0.2	mA		
Ci		VI = 3 V or 0			4			4		pF	
Co		V _O = 3 V or 0			9			9		pF	

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C. [‡] This parameter is characterized but not production tested.

§ This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.



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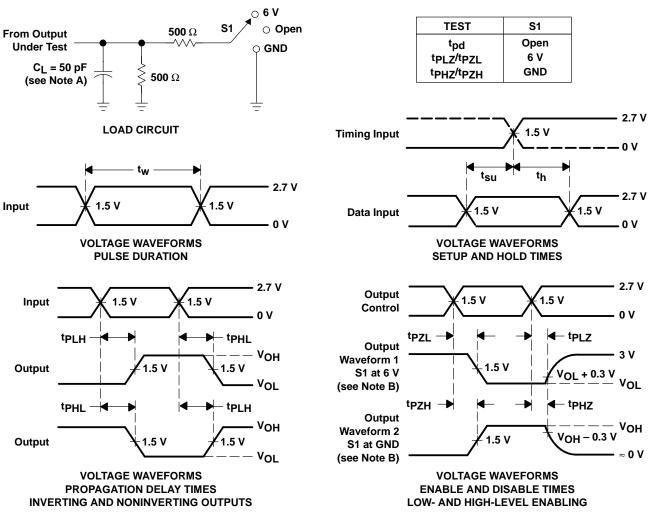
switching characteristics over recommended operating free-air temperature range, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 1)

			SN54LVTH16244A			SN74LVTH16244A						
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 3.3 V ± 0.3 V		V _{CC} =	2.7 V	۷ ₀	CC = 3.3 ± 0.3 V	v	V _{CC} =	2.7 V	UNIT
			MIN	MAX	MIN	MAX	MIN	TYP†	MAX	MIN	MAX	
^t PLH	А	Y	1.1	3.4	Ŋ	3.9	1.2	2.3	3.2		3.7	ns
^t PHL	A	T	1.1	3.4	M	3.9	1.2	2	3.2		3.7	115
^t PZH	OE	Y	1.1	4.2	RE	5.2	1.2	2.6	4		5	ns
^t PZL	ÛE	I	1.1	4.2	1.	5.2	1.2	2.7	4		5	115
^t PHZ	OE	v	2.1	4.7		5.2	2.2	3.3	4.5		5	ns
^t PLZ	UE	I	1.9	4.5		4.7	2	3.1	4.2		4.4	115
^t sk(o)				2					0.5			ns

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25° C.



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PARAMETER MEASUREMENT INFORMATION

NOTES: A. CI includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control.
- Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control. C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_Q = 50 Ω , t_r \leq 2.5 ns, t_f \leq 2.5 ns.
- C. All input puises are supplied by generators having the following characteristics: PRR \leq 10 MHz, 20 = 50 Ω, t_f \leq 2.5 ns, t_f \leq 2.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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